

TOSHIBA INSULATED GATE BIPOLAR TRANSISTOR SILICON N CHANNEL IGBT

# GT60M303

#### HIGH POWER SWITCHING APPLICATIONS

• Fourth generation IGBT

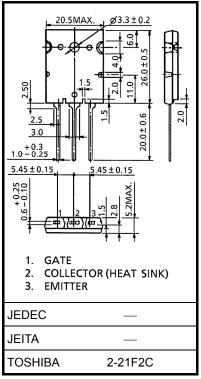
- FRD included between emitter and collector
- Enhancement mode type
- High speed  $I_{GBT}$  :  $t_f = 0.25 \mu s$  (TYP.)

FRD  $: t_{rr} = 0.7 \mu s$  (TYP.)

• Low saturation voltage : V<sub>CE</sub> (sat) = 2.1V (TYP.)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Emitter Voltage		V <sub>CES</sub>	900	V	
Gate-Emitter Voltage		V <sub>GES</sub>	±25	V	
Collector Current	DC	Ι <sub>C</sub>	60	A	
	1ms	I <sub>CP</sub>	120		
Emitter-Collector Foward Current	DC	I <sub>ECF</sub>	15	A	
	1ms	IECFP	120		
Collector Power Dissipation (Tc = 25°C)		PC	170	W	
Junction Temperature		Tj	150	°C	
Storage Temperature Range		T <sub>stg</sub>	-55~150	°C	
Screw Torque		—	0.8	N∙m	

### ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

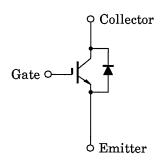


Weight: 9.75 g (typ.)

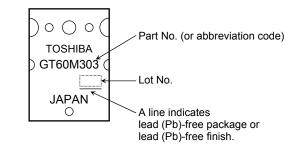
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **EQUIVALENT CIRCUIT**



### MARKING

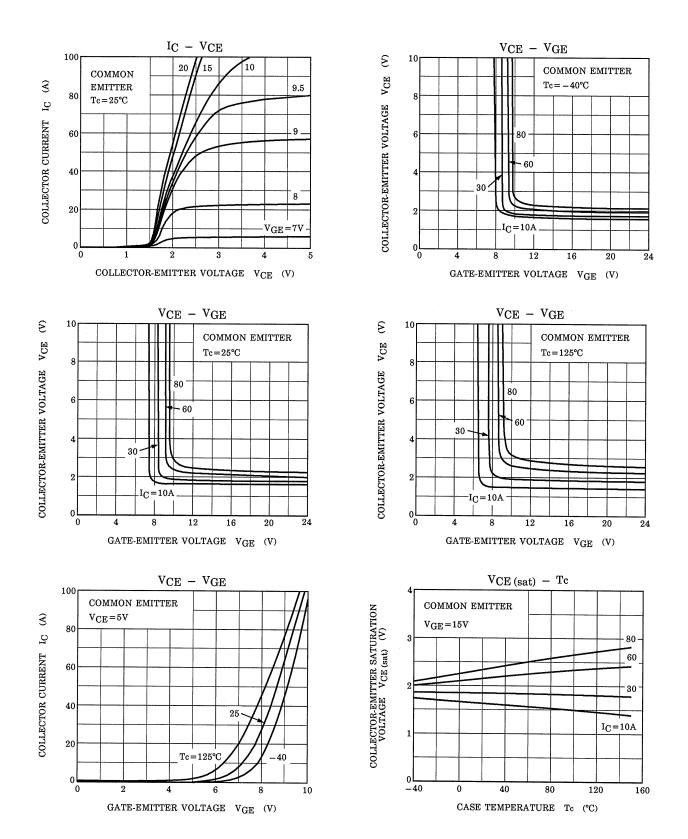


Unit: mm

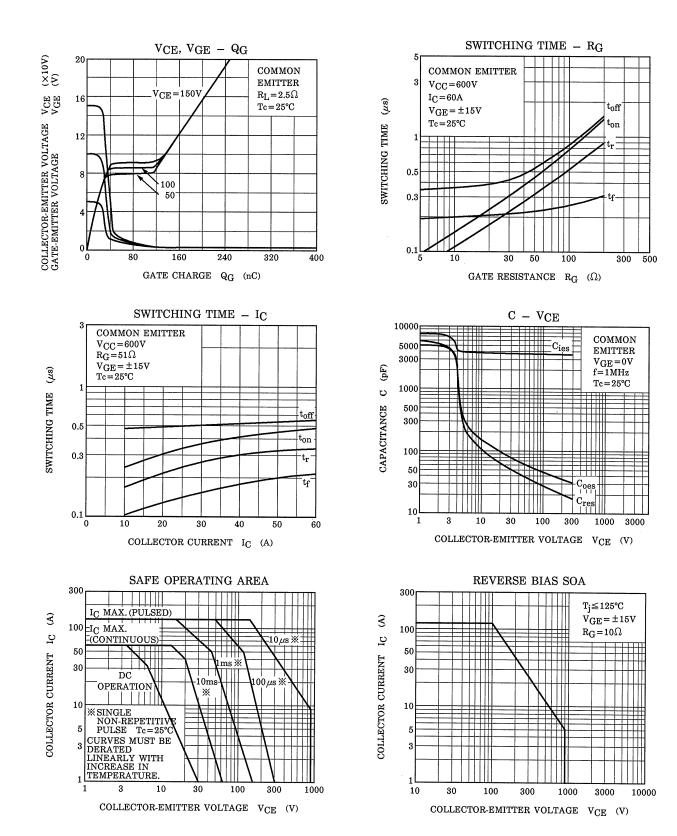
### ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Gate Leakage Current		I <sub>GES</sub>	$V_{GE}$ = ±25V, $V_{CE}$ = 0	_	—	±500	nA
Collector Cut-off Current		ICES	V <sub>CE</sub> = 900V, V <sub>GE</sub> = 0		_	1.0	mA
Gate-Emitter Cut-off Voltage		V <sub>GE (OFF)</sub>	I <sub>C</sub> = 60mA, V <sub>CE</sub> = 5V	3.0	_	6.0	V
Collector-Emitter Saturation Voltage		V <sub>CE (sat) (1)</sub>	I <sub>C</sub> = 10A, V <sub>GE</sub> = 15V		1.6	2.2	V
Collector-Emitter Saturation Voltage		V <sub>CE (sat) (2)</sub>	I <sub>C</sub> = 60A, V <sub>GE</sub> = 15V		2.1	2.7	V
Input Capacitance		Cies	V <sub>CE</sub> = 10V, V <sub>GE</sub> = 0, f = 1MHz		3800	_	pF
Switching Time	Rise Time	tr	$15V_{0} \qquad \qquad$		0.35	0.60	μs
	Turn-On Time	t <sub>on</sub>			0.46	0.75	
	Fall Time	t <sub>f</sub>			0.25	0.40	
	Turn-Off Time	t <sub>off</sub>			0.60	0.70	
Emitter-Collector Forward Voltage		V <sub>ECF</sub>	I <sub>EC</sub> = 15A, V <sub>GE</sub> = 0		1.5	2.0	V
Reverse Recovery Time		t <sub>rr</sub>	I <sub>F</sub> = 15A, V <sub>GE</sub> = 0 di / dt = −20A / μs	_	0.7	2.5	μs
Thermal Resistance		R <sub>th (j−c)</sub>	IGBT	_	_	0.74	°C / W
Thermal Resistance		R <sub>th (j−c)</sub>	Diode	_	_	4.0	°C / W

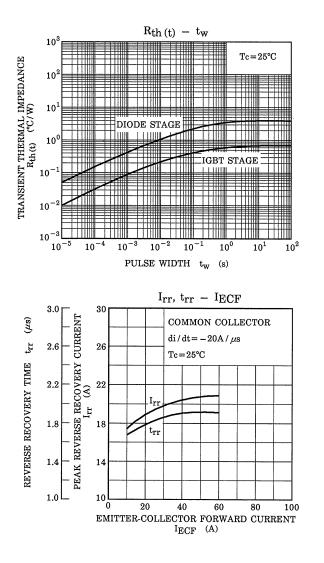
# **TOSHIBA**

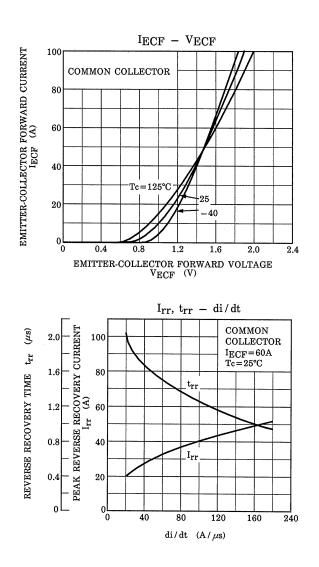


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